Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/519,322	CHEN ET AL.
Examiner	**Art Unit**
Sam K. Ahn	2611

SEARCHED			
Class	Subclass	Date	Examiner
375	216, 280 324/329	8/11	
714	786		
375	262, 279 316, 331		
375	333		
370	209	8/11	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST, IEEE & google inventor, keyword & citation search	8/11	